


<b>Search Notes</b>  	<b>Application/Control No.</b>  10605944	<b>Applicant(s)/Patent Under Reexamination</b>  BOUDON ET AL.
	<b>Examiner</b>  Wai, Eric C	<b>Art Unit</b>  2195

SEARCHED			
Class	Subclass	Date	Examiner
718	100	07/09/2007	ECW
365	221	12/14/2007	ECW

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor's Name Search	07/09/2007	ECW
East Search	07/09/2007	ECW
Updated East Search	12/14/2007	ECW
Google Scholar Search	12/14/2007	ECW

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner